

# STF26N60M2, STFI26N60M2

# N-channel 600 V, 0.14 Ω typ., 20 A MDmesh™ M2 Power MOSFETs in TO-220FP and I²PAKFP packages

Datasheet - production data

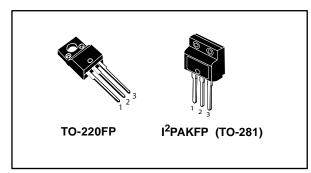
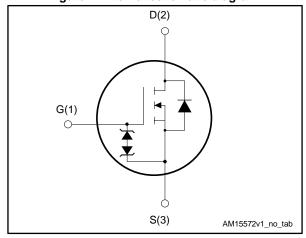


Figure 1: Internal schematic diagram



#### **Features**

Order code	V <sub>DS</sub> @ T <sub>Jmax</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>	Ртот
STF26N60M2	650 V	0.165.0	20 A	30
STFI26N60M2	650 V	0.165 Ω 2	20 A	W

- Extremely low gate charge
- Excellent output capacitance (C<sub>OSS</sub>) profile
- 100% avalanche tested
- Zener-protected

### **Applications**

- Switching applications
- LCC converters, resonant converters

### **Description**

These devices are N-channel Power MOSFETs developed using MDmesh™ M2 technology. Thanks to their strip layout and improved vertical structure, these devices exhibit low on-resistance and optimized switching characteristics, rendering them suitable for the most demanding high efficiency converters.

**Table 1: Device summary** 

Order code	Marking	Package	Packing
STF26N60M2	26N60M2	TO-220FP	Tube
STFI26N60M2	2011001112	I²PAKFP	Tube

### **Contents**

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### 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	±25	V
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at T <sub>case</sub> = 25 °C	20	А
ID	Drain current (continuous) at T <sub>case</sub> = 100 °C	13	А
I <sub>DM</sub> <sup>(2)</sup>	Drain current (pulsed)	80	Α
P <sub>TOT</sub>	Total dissipation at T <sub>case</sub> = 25 °C	30	W
dv/dt <sup>(3)</sup>	Peak diode recovery voltage slope	15	V/ns
dv/dt <sup>(4)</sup>	MOSFET dv/dt ruggedness	50	V/IIS
V <sub>ISO</sub>	Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s; $T_C$ = 25 °C)	2.5	kV
T <sub>stg</sub>	Storage temperature	55 to 150	°C
T <sub>j</sub>	Operating junction temperature	-55 to 150	C

#### Notes:

Table 3: Thermal data

Symbol	Parameter		Unit	
R <sub>thj-case</sub>	Thermal resistance junction-case	4.2	0000	
R <sub>thj-amb</sub>	Thermal resistance junction-ambient	62.5	°C/W	

**Table 4: Avalanche characteristics** 

Symbol	Parameter	Value	Unit
I <sub>AR</sub> <sup>(1)</sup>	Avalanche current, repetitive or not repetitive	3.8	Α
E <sub>AR</sub> <sup>(2)</sup>	Single pulse avalanche energy	250	mJ

#### Notes:

<sup>&</sup>lt;sup>(1)</sup> Limited by maximum junction temperature.

 $<sup>^{\</sup>left( 2\right) }$  Pulse width is limited by safe operating area.

 $<sup>^{(3)}</sup>$   $I_{SD} \leq 20$  A, di/dt=400 A/µs;  $V_{DS(peak)} < V_{(BR)DSS}, \ V_{DD} = 80\% \ V_{(BR)DSS}.$ 

 $<sup>^{(4)}</sup> V_{DS} \le 480 V.$ 

 $<sup>^{\</sup>left(1\right)}$  Pulse width limited by  $T_{jmax}.$ 

 $<sup>^{(2)}</sup>$  starting  $T_{j}$  = 25 °C,  $I_{D}$  =  $I_{AR},\,V_{DD}$  = 50 V.

### 2 Electrical characteristics

(T<sub>case</sub> = 25 °C unless otherwise specified)

Table 5: Static

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	600			٧
Zoro goto voltogo droin		$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}$			1	
I <sub>DSS</sub> Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V},$ $T_{case} = 125 \text{ °C}$			100	μΑ	
I <sub>GSS</sub>	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			±10	μΑ
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	3	4	V
R <sub>DS(on)</sub>	Static drain-source on- resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10 A		0.14	0.165	Ω

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>iss</sub>	Input capacitance		-	1360	•	
Coss	Output capacitance	V <sub>DS</sub> = 100 V, f = 1 MHz,	-	88	ı	pF
C <sub>rss</sub>	Reverse transfer capacitance	$V_{GS} = 0 V$	-	2	-	ρ.
Coss eq. (1)	Equivalent output capacitance	$V_{DS} = 0$ to 480 V, $V_{GS} = 0$ V	-	124	-	pF
$R_{G}$	Intrinsic gate resistance	f = 1 MHz, I <sub>D</sub> = 0 A	-	4	-	Ω
Qg	Total gate charge	$V_{DD} = 480 \text{ V}, I_{D} = 20 \text{ A},$	-	34	•	
$Q_{gs}$	Gate-source charge	V <sub>GS</sub> = 10 V (see <i>Figure 15</i> :	-	5.6	1	nC
$Q_{gd}$	Gate-drain charge	"Gate charge test circuit")	-	16.3	-	

#### Notes:

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time	$V_{DD} = 300 \text{ V}, I_D = 10 \text{ A}$	-	20.2	-	
t <sub>r</sub>	Rise time	$R_G = 4.7 \Omega$ , $V_{GS} = 10 V$ (see Figure 14: "Switching times	-	8	-	
t <sub>d(off)</sub>	Turn-off delay time	test circuit for resistive load"	-	66	-	ns
t <sub>f</sub>	Fall time	and Figure 19: "Switching time waveform")	-	10	-	



 $<sup>^{(1)}</sup>$   $C_{oss\ eq.}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

Table 8: Source-drain diode

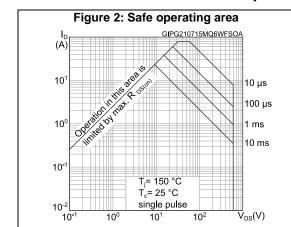
Symbol	Parameter	Test conditions		Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		-		20	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		80	Α
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 20 A	-		1.6	V
t <sub>rr</sub>	Reverse recovery time	$I_{SD} = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$	-	360		ns
$Q_{rr}$	Reverse recovery charge	V <sub>DD</sub> = 60 V (see Figure 16: "Test circuit for inductive load	-	5		μC
I <sub>RRM</sub>	Reverse recovery current	switching and diode recovery times")	ı	27		Α
t <sub>rr</sub>	Reverse recovery time	$I_{SD} = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$	-	556		ns
Q <sub>rr</sub>	Reverse recovery charge	$V_{DD}$ = 60 V, $T_j$ = 150 °C (see Figure 16: "Test circuit for	-	8		μC
I <sub>RRM</sub>	Reverse recovery current	inductive load switching and diode recovery times")	-	29		Α

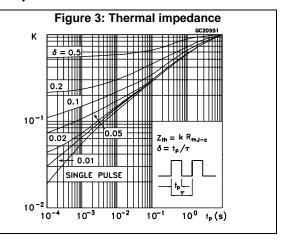
#### Notes:

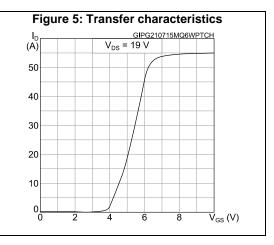
 $<sup>^{\</sup>left( 1\right) }$  Pulse width is limited by safe operating area.

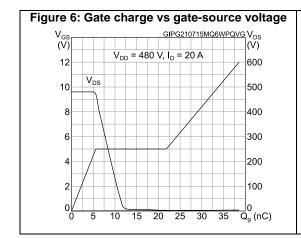
 $<sup>^{(2)}</sup>$  Pulse test: pulse duration = 300  $\mu s,$  duty cycle 1.5%.

### 2.1 Electrical characteristics (curves)









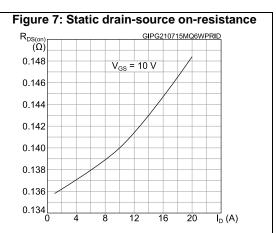


Figure 8: Capacitance variations

C
(pF)

103

C
Clss

Coss

101

f = 1 MHz

Coss

1001

1001

1001

1001

1001

1001

1002

Coss

C

Figure 10: Normalized on-resistance vs temperature

R<sub>DS(on)</sub> GIPG210715MQ6WPRON
(norm.)

2.4

2.0

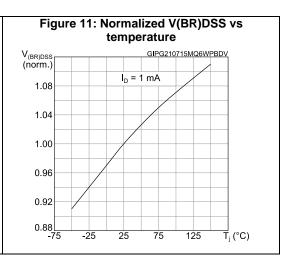
1.6

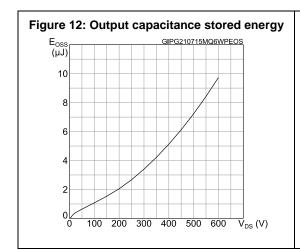
1.2

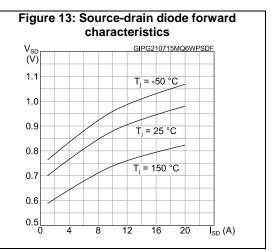
0.8

0.4

-75
-25
25
75
125
T<sub>j</sub> (°C)







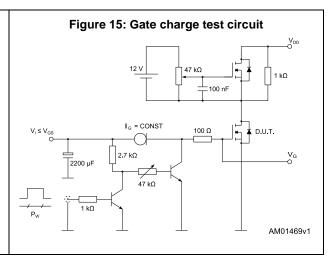
### 3 Test circuits

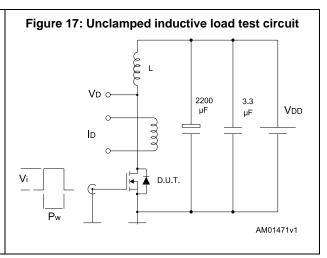
Figure 14: Switching times test circuit for resistive load

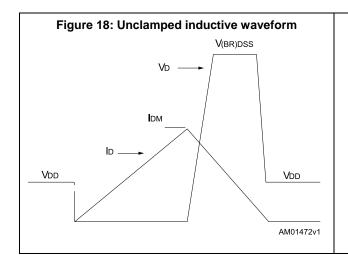
RL 2200 3.3 µF VDD

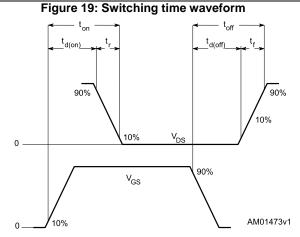
VB RG D.U.T.

AM01468v1









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### 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

# 4.1 TO-220FP package information

Figure 20: TO-220FP package outline

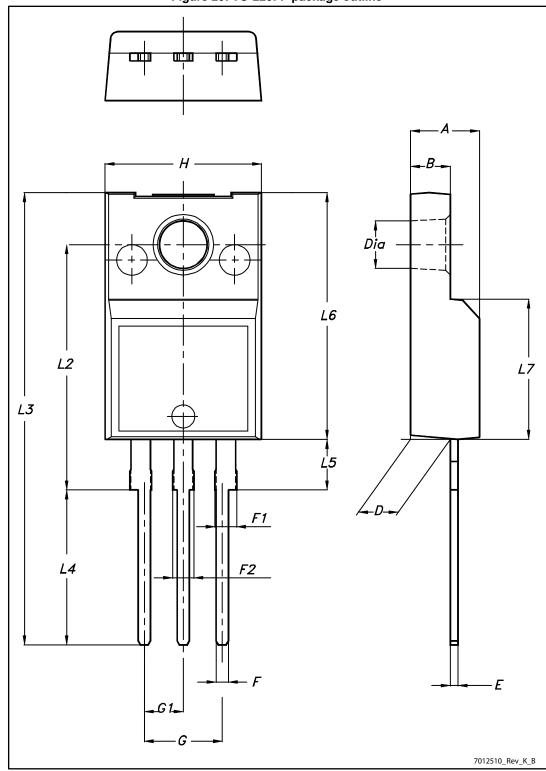


Table 9: TO-220FP package mechanical data

<b>D</b> !		mm	
Dim.	Min.	Тур.	Max.
A	4.4		4.6
В	2.5		2.7
D	2.5		2.75
Е	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.2
G1	2.4		2.7
Н	10		10.4
L2		16	
L3	28.6		30.6
L4	9.8		10.6
L5	2.9		3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2

# 4.2 I<sup>2</sup>PAKFP (TO-281) package information

Figure 21: I<sup>2</sup>PAKFP (TO-281) package outline

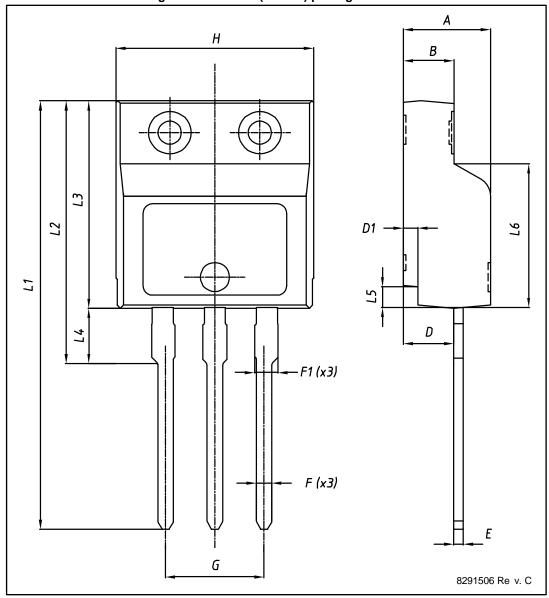


Table 10: I<sup>2</sup>PAKFP (TO-281) mechanical data

Dim	,	mm	
Dim.	Min.	Тур.	Max.
A	4.40	-	4.60
В	2.50		2.70
D	2.50		2.75
D1	0.65		0.85
Е	0.45		0.70
F	0.75		1.00
F1			1.20
G	4.95		5.20
Н	10.00		10.40
L1	21.00		23.00
L2	13.20		14.10
L3	10.55		10.85
L4	2.70		3.20
L5	0.85		1.25
L6	7.50	7.60	7.70

### 5 Revision history

**Table 11: Document revision history** 

Date	Revision	Changes
05-Mar-2015	1	First release.
30-July-2015	2	Text and formatting changes throughout document Datasheet promoted from preliminary data to production data In Section <i>Electrical characteristics</i> : - updated and renamed table <i>Static</i> (was On/off states) - updated table <i>Dynamic</i> , <i>Switching times</i> and <i>Source-drain diode</i> - added section <i>Electrical characteristics</i> (curves)

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